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J. Best

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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Patent application

Attorney Docket No. B-028

of Jill R. Scott, et al

for Laser Device

the specification of which is being transmitted herewith

Assistant Commissioner for Patents  
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT**

References -- See attached form PTO-1449.

The attached form PTO-1449 is submitted in compliance with 37 CFR 1.56.

No admission is made as respects the attached documents or their contents.

RESPECTFULLY SUBMITTED,

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. B-028		SERIAL NO. Unknown	
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT Jill R. Scott, et al			
				FILING DATE Herewith		GROUP Unknown	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes      No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Scott, J. R., et al, "Development of an Imaging Internal Laser Desorption Fourier Transform Mass Spectrometer," Pittsburg, PA March 4-9, 2001, page 143.				
			Tremblay, P. L., et al, "An Automated Imaging Internal Laser Desorption Fourier Transform Mass Spectrometer for Surface Analysis," <u>49<sup>th</sup> ASMS Conference on Mass Spectrometry and Allied Topics</u> , Chicago, IL May 26-31, 2001.				
	AS		Tremblay, P. L., et al "Laser Scanning Design for a Fourier Transform Mass Spectrometer," <u>48<sup>th</sup> ASMS Conference on Mass Spectrometry and Allied Topics</u> , Long Beach, CA June 11-15, 2000.				
	AT						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							